



FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MICRON.140DV1C1APPLICATION NO.  
10/757,638INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT

(USE SEVERAL SHEETS IF NECESSARY)

APPLICANT  
Li et al.FILING DATE  
January 13, 2004GROUP  
~~Unknown~~

2824

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
MKL	1	6,475,854	11/2002	Narwankar et al.			
MKL	2	6,403,414	06/2002	Marsh			
MKL	3	6,271,131	08/2001	Uhlenbrock et al.			
MKL	4	6,201,271	03/2001	Okutoh et al.			
MKL	5	6,180,974	01/2001	Okutoh et al.			
MKL	6	6,140,230	10/2000	Li			
MKL	7	5,902,651	05/1999	Westmoreland et al.			
MKL	8	5,783,716	07/1998	Baum et al.			
MKL	9	5,763,007	06/1998	Weiller			
MKL	10	5,672,385	09/1997	Jimba et al.			
MKL	11	5,576,071	11/1996	Sandhu			
MKL	12	5,552,327	09/1996	Bachmann et al.			
MKL	13	5,130,172	07/1992	Hicks et al.			
MKL	14	US 2001/0000865 A1	05/2001	Gaughen et al.			
MKL	15	US 2001/0043453 A1	11/2001	Narwankar et al.			
MKL	16	US 2001/0044207 A1	11/2001	Marsh			
MKL	17	US 2002/0076492 A1	06/2002	Loan et al.			

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)	
MKL	18	Irving, Optical Diagnostics for Thin Film Processing, Academic Press, 1996, page 29.
	19	

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EXAMINER	<i>Michael F. Lutz</i>	DATE CONSIDERED	7/19/04
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